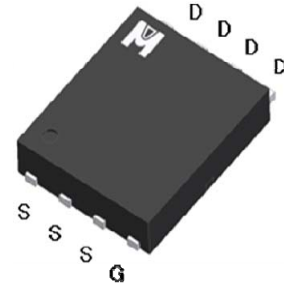
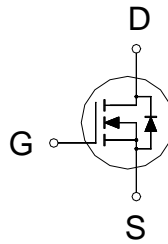


N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV_{DSS}	30V
$R_{DS(on)}$ (MAX.)	2.1m Ω
I_D	100A



UIS, R_g 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS ($T_A = 25\text{ }^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current ¹	$T_C = 25\text{ }^\circ\text{C}$	I_D	100	A
	$T_C = 100\text{ }^\circ\text{C}$		75	
Pulsed Drain Current ²		I_{DM}	400	
Avalanche Current		I_{AS}	65	
Avalanche Energy	$L = 0.1\text{mH}, I_D = 65\text{A}, R_G = 25\text{ }\Omega$	E_{AS}	211	mJ
Repetitive Avalanche Energy ³	$L = 0.05\text{mH}$	E_{AR}	105	
Power Dissipation	$T_C = 25\text{ }^\circ\text{C}$	P_D	50	W
	$T_C = 100\text{ }^\circ\text{C}$		20	
Operating Junction & Storage Temperature Range		T_{j}, T_{stg}	-55 to 150	$^\circ\text{C}$

100% UIS testing in condition of $V_D = 15\text{V}, L = 0.1\text{mH}, V_G = 10\text{V}, I_L = 40\text{A}$, Rated $V_{DS} = 30\text{V}$ N-CH

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	$R_{\theta JC}$		2.5	$^\circ\text{C} / \text{W}$
Junction-to-Ambient ⁴	$R_{\theta JA}$		50	

¹Package Limited.

²Pulse width limited by maximum junction temperature.

³Duty cycle $\leq 1\%$

⁴50 $^\circ\text{C} / \text{W}$ when mounted on a 1 in² pad of 2 oz copper.



ELECTRICAL CHARACTERISTICS ($T_J = 25\text{ }^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	30			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	1.5	3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 24V, V_{GS} = 0V$			1	μA
		$V_{DS} = 20V, V_{GS} = 0V, T_J = 125\text{ }^\circ\text{C}$			25	
On-State Drain Current ¹	$I_{D(ON)}$	$V_{DS} = 10V, V_{GS} = 10V$	100			A
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 25A$		1.8	2.1	$m\Omega$
		$V_{GS} = 4.5V, I_D = 15A$		2.7	3.3	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 25A$		70		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$		3813		pF
Output Capacitance	C_{oss}			540		
Reverse Transfer Capacitance	C_{rss}			440		
Gate Resistance	R_g	$V_{GS} = 15mV, V_{DS} = 0V, f = 1MHz$		1.5		Ω
Total Gate Charge ^{1,2}	$Q_g(V_{GS}=10V)$	$V_{DS} = 15V, V_{GS} = 10V,$ $I_D = 25A$		59		nC
	$Q_g(V_{GS}=4.5V)$			28		
Gate-Source Charge ^{1,2}	Q_{gs}			13		
Gate-Drain Charge ^{1,2}	Q_{gd}			11		
Turn-On Delay Time ^{1,2}	$t_{d(on)}$		$V_{DS} = 15V,$ $I_D = 1A, V_{GS} = 10V, R_{GS} = 2.7\Omega$		25	
Rise Time ^{1,2}	t_r			16		
Turn-Off Delay Time ^{1,2}	$t_{d(off)}$			60		
Fall Time ^{1,2}	t_f			25		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_C = 25\text{ }^\circ\text{C}$)						
Continuous Current ⁴	I_S				100	A
Pulsed Current ³	I_{SM}				400	
Forward Voltage ¹	V_{SD}	$I_F = 30A, V_{GS} = 0V$			1.2	V
Reverse Recovery Time	t_{rr}	$I_F = I_S, di_F/dt = 100A / \mu S$		35		nS
Peak Reverse Recovery Current	$I_{RM(REC)}$			200		A
Reverse Recovery Charge	Q_{rr}			25		nC

¹Pulse test : Pulse Width $\leq 300 \mu\text{sec}$, Duty Cycle $\leq 2\%$.

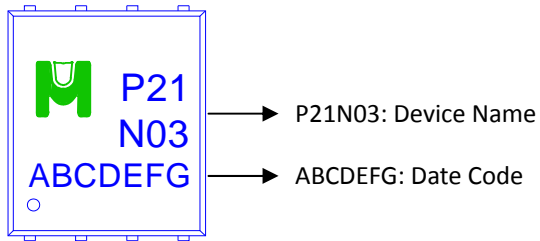
²Independent of operating temperature.

³Pulse width limited by maximum junction temperature.

⁴Package Limited.

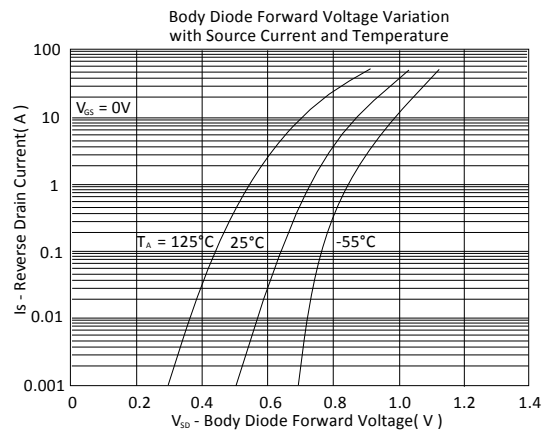
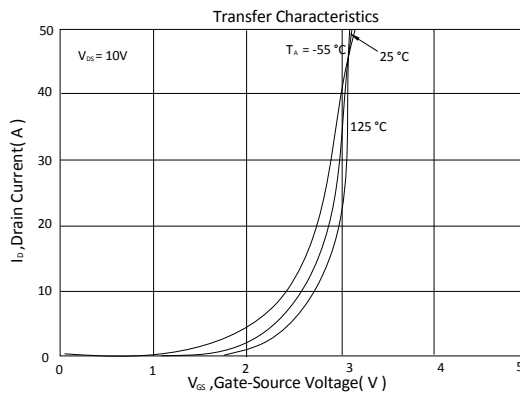
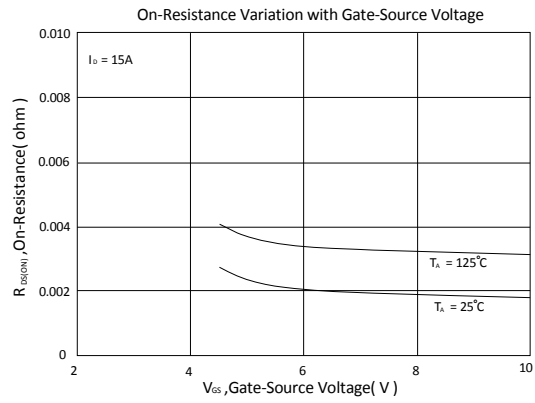
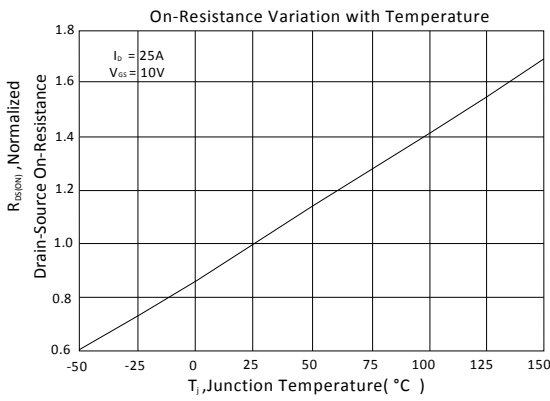
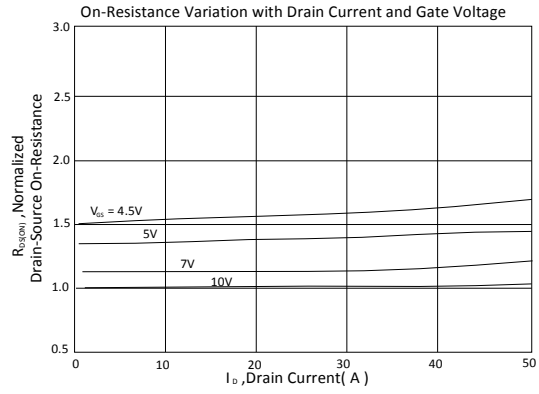
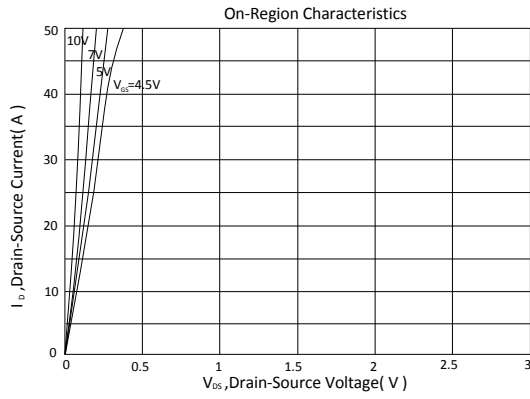
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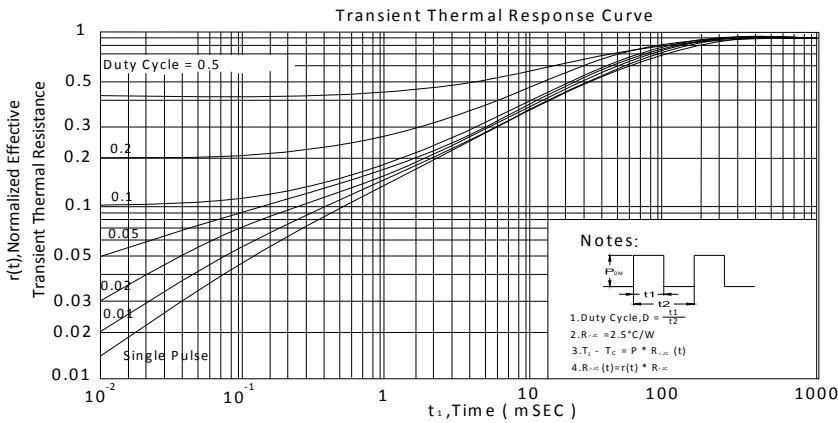
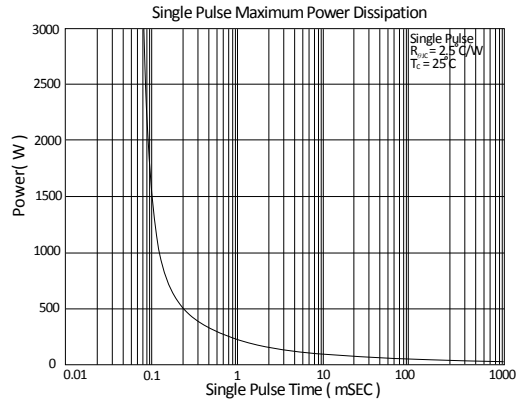
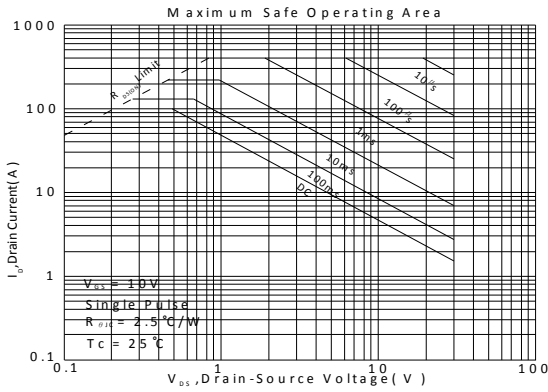
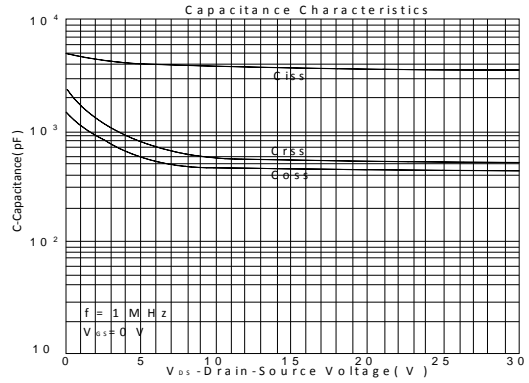
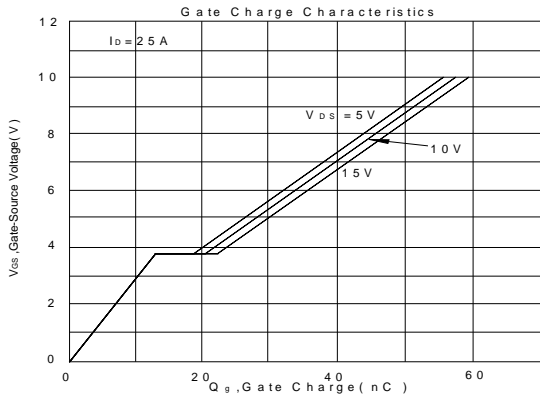
Device Name: EMP21N03HC for EDFN 5 x 6





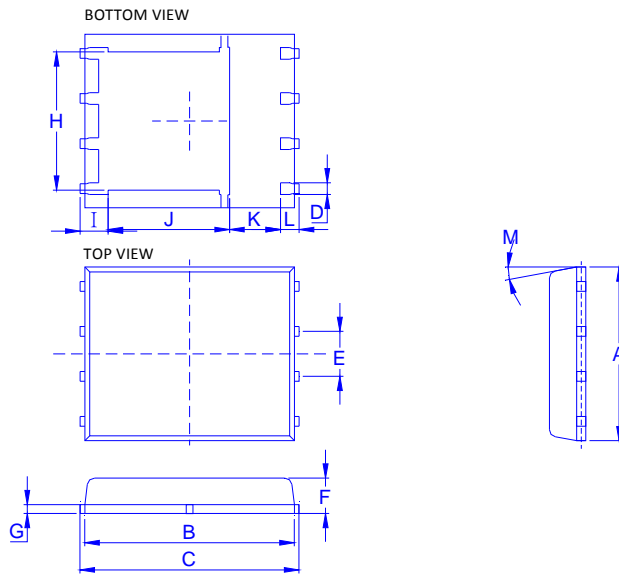
TYPICAL CHARACTERISTICS







Outline Drawing



Dimension in mm

Dimension	A	B	C	D	E	F	G	H	I	J	K	L	M
Min.	4.80	5.50	5.90	0.3		0.85	0.15	3.67	0.41	3.00	0.94	0.45	0°
Typ.					1.27								
Max.	5.30	5.90	6.15	0.51		1.20	0.30	4.54	0.85	3.92	1.7	0.71	12°

Recommended minimum pads

